

To our customers,

---

## Old Company Name in Catalogs and Other Documents

---

On April 1<sup>st</sup>, 2010, NEC Electronics Corporation merged with Renesas Technology Corporation, and Renesas Electronics Corporation took over all the business of both companies. Therefore, although the old company name remains in this document, it is a valid Renesas Electronics document. We appreciate your understanding.

Renesas Electronics website: <http://www.renesas.com>

April 1<sup>st</sup>, 2010  
Renesas Electronics Corporation

Issued by: Renesas Electronics Corporation (<http://www.renesas.com>)

Send any inquiries to <http://www.renesas.com/inquiry>.

## Notice

1. All information included in this document is current as of the date this document is issued. Such information, however, is subject to change without any prior notice. Before purchasing or using any Renesas Electronics products listed herein, please confirm the latest product information with a Renesas Electronics sales office. Also, please pay regular and careful attention to additional and different information to be disclosed by Renesas Electronics such as that disclosed through our website.
2. Renesas Electronics does not assume any liability for infringement of patents, copyrights, or other intellectual property rights of third parties by or arising from the use of Renesas Electronics products or technical information described in this document. No license, express, implied or otherwise, is granted hereby under any patents, copyrights or other intellectual property rights of Renesas Electronics or others.
3. You should not alter, modify, copy, or otherwise misappropriate any Renesas Electronics product, whether in whole or in part.
4. Descriptions of circuits, software and other related information in this document are provided only to illustrate the operation of semiconductor products and application examples. You are fully responsible for the incorporation of these circuits, software, and information in the design of your equipment. Renesas Electronics assumes no responsibility for any losses incurred by you or third parties arising from the use of these circuits, software, or information.
5. When exporting the products or technology described in this document, you should comply with the applicable export control laws and regulations and follow the procedures required by such laws and regulations. You should not use Renesas Electronics products or the technology described in this document for any purpose relating to military applications or use by the military, including but not limited to the development of weapons of mass destruction. Renesas Electronics products and technology may not be used for or incorporated into any products or systems whose manufacture, use, or sale is prohibited under any applicable domestic or foreign laws or regulations.
6. Renesas Electronics has used reasonable care in preparing the information included in this document, but Renesas Electronics does not warrant that such information is error free. Renesas Electronics assumes no liability whatsoever for any damages incurred by you resulting from errors in or omissions from the information included herein.
7. Renesas Electronics products are classified according to the following three quality grades: “Standard”, “High Quality”, and “Specific”. The recommended applications for each Renesas Electronics product depends on the product’s quality grade, as indicated below. You must check the quality grade of each Renesas Electronics product before using it in a particular application. You may not use any Renesas Electronics product for any application categorized as “Specific” without the prior written consent of Renesas Electronics. Further, you may not use any Renesas Electronics product for any application for which it is not intended without the prior written consent of Renesas Electronics. Renesas Electronics shall not be in any way liable for any damages or losses incurred by you or third parties arising from the use of any Renesas Electronics product for an application categorized as “Specific” or for which the product is not intended where you have failed to obtain the prior written consent of Renesas Electronics. The quality grade of each Renesas Electronics product is “Standard” unless otherwise expressly specified in a Renesas Electronics data sheets or data books, etc.
  - “Standard”: Computers; office equipment; communications equipment; test and measurement equipment; audio and visual equipment; home electronic appliances; machine tools; personal electronic equipment; and industrial robots.
  - “High Quality”: Transportation equipment (automobiles, trains, ships, etc.); traffic control systems; anti-disaster systems; anti-crime systems; safety equipment; and medical equipment not specifically designed for life support.
  - “Specific”: Aircraft; aerospace equipment; submersible repeaters; nuclear reactor control systems; medical equipment or systems for life support (e.g. artificial life support devices or systems), surgical implantations, or healthcare intervention (e.g. excision, etc.), and any other applications or purposes that pose a direct threat to human life.
8. You should use the Renesas Electronics products described in this document within the range specified by Renesas Electronics, especially with respect to the maximum rating, operating supply voltage range, movement power voltage range, heat radiation characteristics, installation and other product characteristics. Renesas Electronics shall have no liability for malfunctions or damages arising out of the use of Renesas Electronics products beyond such specified ranges.
9. Although Renesas Electronics endeavors to improve the quality and reliability of its products, semiconductor products have specific characteristics such as the occurrence of failure at a certain rate and malfunctions under certain use conditions. Further, Renesas Electronics products are not subject to radiation resistance design. Please be sure to implement safety measures to guard them against the possibility of physical injury, and injury or damage caused by fire in the event of the failure of a Renesas Electronics product, such as safety design for hardware and software including but not limited to redundancy, fire control and malfunction prevention, appropriate treatment for aging degradation or any other appropriate measures. Because the evaluation of microcomputer software alone is very difficult, please evaluate the safety of the final products or system manufactured by you.
10. Please contact a Renesas Electronics sales office for details as to environmental matters such as the environmental compatibility of each Renesas Electronics product. Please use Renesas Electronics products in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances, including without limitation, the EU RoHS Directive. Renesas Electronics assumes no liability for damages or losses occurring as a result of your noncompliance with applicable laws and regulations.
11. This document may not be reproduced or duplicated, in any form, in whole or in part, without prior written consent of Renesas Electronics.
12. Please contact a Renesas Electronics sales office if you have any questions regarding the information contained in this document or Renesas Electronics products, or if you have any other inquiries.

(Note 1) “Renesas Electronics” as used in this document means Renesas Electronics Corporation and also includes its majority-owned subsidiaries.

(Note 2) “Renesas Electronics product(s)” means any product developed or manufactured by or for Renesas Electronics.

To all our customers

---

## **Regarding the change of names mentioned in the document, such as Hitachi Electric and Hitachi XX, to Renesas Technology Corp.**

---

The semiconductor operations of Mitsubishi Electric and Hitachi were transferred to Renesas Technology Corporation on April 1st 2003. These operations include microcomputer, logic, analog and discrete devices, and memory chips other than DRAMs (flash memory, SRAMs etc.) Accordingly, although Hitachi, Hitachi, Ltd., Hitachi Semiconductors, and other Hitachi brand names are mentioned in the document, these names have in fact all been changed to Renesas Technology Corp. Thank you for your understanding. Except for our corporate trademark, logo and corporate statement, no changes whatsoever have been made to the contents of the document, and these changes do not constitute any alteration to the contents of the document itself.

Renesas Technology Home Page: <http://www.renesas.com>

Renesas Technology Corp.  
Customer Support Dept.  
April 1, 2003

# E8000 SH7060 Emulator

Diagnostic Program Manual



## Cautions

1. Hitachi neither warrants nor grants licenses of any rights of Hitachi's or any third party's patent, copyright, trademark, or other intellectual property rights for information contained in this document. Hitachi bears no responsibility for problems that may arise with third party's rights, including intellectual property rights, in connection with use of the information contained in this document.
2. Products and product specifications may be subject to change without notice. Confirm that you have received the latest product standards or specifications before final design, purchase or use.
3. Hitachi makes every attempt to ensure that its products are of high quality and reliability. However, contact Hitachi's sales office before using the product in an application that demands especially high quality and reliability or where its failure or malfunction may directly threaten human life or cause risk of bodily injury, such as aerospace, aeronautics, nuclear power, combustion control, transportation, traffic, safety equipment or medical equipment for life support.
4. Design your application so that the product is used within the ranges guaranteed by Hitachi particularly for maximum rating, operating supply voltage range, heat radiation characteristics, installation conditions and other characteristics. Hitachi bears no responsibility for failure or damage when used beyond the guaranteed ranges. Even within the guaranteed ranges, consider normally foreseeable failure rates or failure modes in semiconductor devices and employ systemic measures such as fail-safes, so that the equipment incorporating Hitachi product does not cause bodily injury, fire or other consequential damage due to operation of the Hitachi product.
5. This product is not designed to be radiation resistant.
6. No one is permitted to reproduce or duplicate, in any form, the whole or part of this document without written approval from Hitachi.
7. Contact Hitachi's sales office for any questions regarding this document or Hitachi semiconductor products.



# IMPORTANT INFORMATION

## READ FIRST

- **READ this user's manual before using this emulator product.**
- **KEEP the user's manual handy for future reference.**

**Do not attempt to use the emulator product until you fully understand its mechanism.**

### **Emulator Product:**

Throughout this document, the term "emulator product" shall be defined as the following products produced only by Hitachi, Ltd. excluding all subsidiary products.

- Emulator station
- Device control board
- EV-chip board
- User system interface cable

The user system or a host computer is not included in this definition.

### **Purpose of the Emulator Product:**

This emulator product is a software and hardware development tool for systems employing the Hitachi microcomputer HD64F7065 (hereinafter referred to as SH7060). By exchanging the device control board and EV-chip board, this emulator product can also be used for systems using Hitachi microcomputers supported by other E8000-series emulators. This emulator product must only be used for the above purpose.

### **Limited Applications:**

This emulator product is not authorized for use in MEDICAL, atomic energy, aeronautical or space technology applications without consent of the appropriate officer of a Hitachi sales company. Such use includes, but is not limited to, use in life support systems. Buyers of this emulator product must notify the relevant Hitachi sales offices before planning to use the product in such applications.

### **Improvement Policy:**

Hitachi, Ltd. (including its subsidiaries, hereafter collectively referred to as Hitachi) pursues a policy of continuing improvement in design, performance, and safety of the emulator product. Hitachi reserves the right to change, wholly or partially, the specifications, design, user's manual, and other documentation at any time without notice.

### **Target User of the Emulator Product:**

This emulator product should only be used by those who have carefully read and thoroughly understood the information and restrictions contained in the user's manual. Do not attempt to use the emulator product until you fully understand its mechanism.

It is highly recommended that first-time users be instructed by users that are well versed in the operation of the emulator product.



## **LIMITED WARRANTY**

Hitachi warrants its emulator products to be manufactured in accordance with published specifications and free from defects in material and/or workmanship. Hitachi, at its option, will repair or replace any emulator products returned intact to the factory, transportation charges prepaid, which Hitachi, upon inspection, determine to be defective in material and/or workmanship. The foregoing shall constitute the sole remedy for any breach of Hitachi's warranty. See the Hitachi warranty booklet for details on the warranty period. This warranty extends only to you, the original Purchaser. It is not transferable to anyone who subsequently purchases the emulator product from you. Hitachi is not liable for any claim made by a third party or made by you for a third party.

## **DISCLAIMER**

HITACHI MAKES NO WARRANTIES, EITHER EXPRESS OR IMPLIED, ORAL OR WRITTEN, EXCEPT AS PROVIDED HEREIN, INCLUDING WITHOUT LIMITATION THEREOF, WARRANTIES AS TO MARKETABILITY, MERCHANTABILITY, FITNESS FOR ANY PARTICULAR PURPOSE OR USE, OR AGAINST INFRINGEMENT OF ANY PATENT. IN NO EVENT SHALL HITACHI BE LIABLE FOR ANY DIRECT, INCIDENTAL OR CONSEQUENTIAL DAMAGES OF ANY NATURE, OR LOSSES OR EXPENSES RESULTING FROM ANY DEFECTIVE EMULATOR PRODUCT, THE USE OF ANY EMULATOR PRODUCT, OR ITS DOCUMENTATION, EVEN IF ADVISED OF THE POSSIBILITY OF SUCH DAMAGES. EXCEPT AS EXPRESSLY STATED OTHERWISE IN THIS WARRANTY, THIS EMULATOR PRODUCT IS SOLD "AS IS", AND YOU MUST ASSUME ALL RISK FOR THE USE AND RESULTS OBTAINED FROM THE EMULATOR PRODUCT.

**State Law:**

Some states do not allow the exclusion or limitation of implied warranties or liability for incidental or consequential damages, so the above limitation or exclusion may not apply to you. This warranty gives you specific legal rights, and you may have other rights which may vary from state to state.

**The Warranty is Void in the Following Cases:**

Hitachi shall have no liability or legal responsibility for any problems caused by misuse, abuse, misapplication, neglect, improper handling, installation, repair or modifications of the emulator product without Hitachi's prior written consent or any problems caused by the user system.

**All Rights Reserved:**

This user's manual and emulator product are copyrighted and all rights are reserved by Hitachi. No part of this user's manual, all or part, may be reproduced or duplicated in any form, in hard-copy or machine-readable form, by any means available without Hitachi's prior written consent.

**Other Important Things to Keep in Mind:**

1. Circuitry and other examples described herein are meant merely to indicate the characteristics and performance of Hitachi's semiconductor products. Hitachi assumes no responsibility for any intellectual property claims or other problems that may result from applications based on the examples described herein.
2. No license is granted by implication or otherwise under any patents or other rights of any third party or Hitachi.

**Figures:**

Some figures in this user's manual may show items different from your actual system.

**Limited Anticipation of Danger:**

Hitachi cannot anticipate every possible circumstance that might involve a potential hazard. The warnings in this user's manual and on the emulator product are therefore not all inclusive. Therefore, you must use the emulator product safely at your own risk.

# SAFETY PAGE

## READ FIRST

- **READ** this user's manual before using this emulator product.
- **KEEP** the user's manual handy for future reference.

Do not attempt to use the emulator product until you fully understand its mechanism.

## DEFINITION OF SIGNAL WORDS



This is the safety alert symbol. It is used to alert you to potential personal injury hazards. Obey all safety messages that follow this symbol to avoid possible injury or death.



**DANGER** indicates an imminently hazardous situation which, if not avoided, will result in death or serious injury.



**WARNING** indicates a potentially hazardous situation which, if not avoided, could result in death or serious injury.



**CAUTION** indicates a potentially hazardous situation which, if not avoided, may result in minor or moderate injury.



**CAUTION** used without the safety alert symbol indicates a potentially hazardous situation which, if not avoided, may result in property damage.

**NOTE** emphasizes essential information.

## **WARNING**

Observe the precautions listed below. Failure to do so will result in a **FIRE HAZARD** and will damage the user system and the emulator product or will result in **PERSONAL INJURY**. The **USER PROGRAM** will be **LOST**.

1. Carefully handle the emulator product to prevent receiving an electric shock because the emulator product has a DC power supply. Do not repair or remodel the emulator product by yourself for electric shock prevention and quality assurance.
2. Always switch **OFF** the emulator product and user system before connecting or disconnecting any **CABLES** or **PARTS**.
3. Always before connecting any **CABLES**, make sure that pin 1 on both sides are correctly aligned.
4. Supply power according to the power specifications and do not apply an incorrect power voltage. Use only the provided power cable.

## Warnings on Emulator Usage

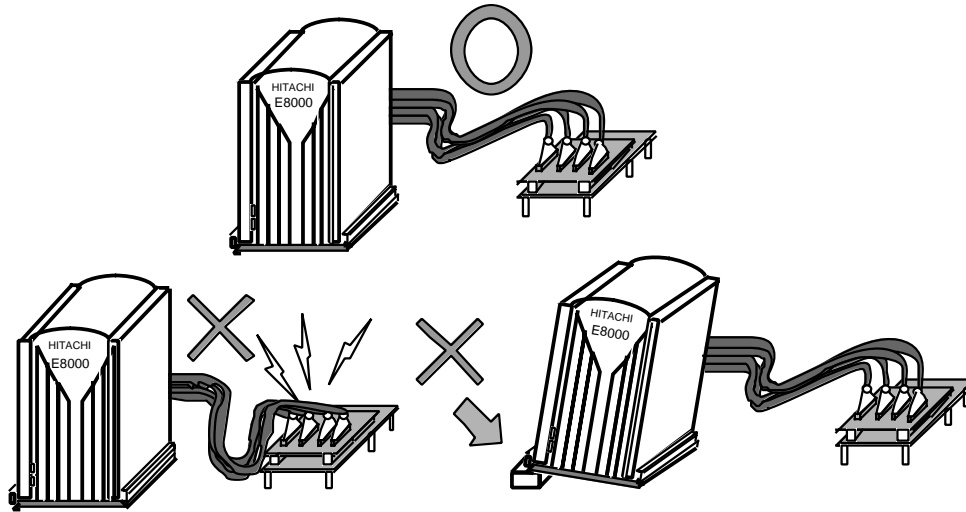
Warnings described below apply as long as you use this emulator. Be sure to read and understand the warnings below before using this emulator. Note that these are the main warnings, not the complete list.

### **WARNING**

**Always switch OFF the emulator and user system before connecting or disconnecting any CABLES or PARTS. Failure to do so will result in a FIRE HAZARD and will damage the user system and the emulator product or will result in PERSONAL INJURY. The USER PROGRAM will be LOST.**

## **⚠ WARNING**

Place the emulator station and EV-chip board so that the trace cables are not bent or twisted. A bent or twisted cable will impose stress on the user interface leading to connection or contact failure. Make sure that the emulator station is placed in a secure position so that it does not move during use nor impose stress on the user interface.



## Preface

Thank you for purchasing the E8000 emulator for Hitachi's original microcomputer SH7060.

The diagnostic program automatically checks whether the E8000 emulator is operating correctly.  
Read this manual and understand it before using the diagnostic program.





# Contents

Section 1 Overview .....	1
1.1 Purpose.....	1
Section 2 Configuration.....	3
2.1 Test System Configuration.....	3
Section 3 Diagnostic Program Function.....	5
3.1 General Description.....	5
3.2 Test Items .....	7
3.3 Operation Flowchart.....	9
3.4 Data Output to the Printer.....	10
Section 4 Diagnostic Program Operation Procedures .....	13
4.1 Installation Procedure.....	14
4.2 Operation Procedure.....	16
Section 5 Error Handling.....	27
Section 6 Testing Circuits and Connectors .....	29
6.1 Testing Circuit for P1284 I/F TEST (TEST07).....	29
6.2 Testing Circuit for SERIAL I/F TEST (TEST08).....	29
6.3 Serial Interface Connector.....	31
6.4 Bidirectional Parallel Interface Connector .....	31



# Section 1 Overview

## 1.1 Purpose

This diagnostic program is used to automatically troubleshoot and maintain an SH7060 E8000 emulator (hereinafter referred to as the E8000 emulator) hardware system. When an error occurs, execute the diagnostic program according to section 4, Diagnostic Program Operation Procedure.

The diagnostic program is on a 3.5-type floppy disk (HS7060EDD81SF).

- Notes:
1. This diagnostic program is not capable of finding all failures possible to occur in the E8000 emulator.
  2. If execution results of the diagnostic program indicate a failure in the E8000 emulator, inform a Hitachi sales agency of the test results in detail.
  3. Hitachi makes no warranties for an E8000 emulator that has been taken apart, repaired, or remodeled by the user based on the test results of the diagnostic program.
  4. In addition to this diagnostic program, run the emulator internal system test described in section 5, Troubleshooting, in the SH7060 E8000 Emulator User's Manual (HS7060EDD81HE).



## Section 2 Configuration

### 2.1 Test System Configuration

Components required for diagnostic program execution are shown in table 2.1, and the test system configuration is shown in figure 2.1.

Table 2.1 Test System Components

<b>Components</b>	<b>Remarks</b>
E8000 emulator (HS8000EST02H)	Device control board (HS7060EDD81H)
	Trace board (HS8000PWB82H)
	Control board (HS8000PWB81H)
	PC I/F board (HS8000PWB85H)
	LAN board (HS7000ELN01H or HS7000ELN02H)
EV-chip board (HS7060EBK81H)	
Serial interface cable (RS232C)	
Bidirectional parallel interface cable (P1284)	
Host computer (DOS/V machine)	
System floppy disk (HS7060EDD81SF) (Host interface software (IPW) included)	

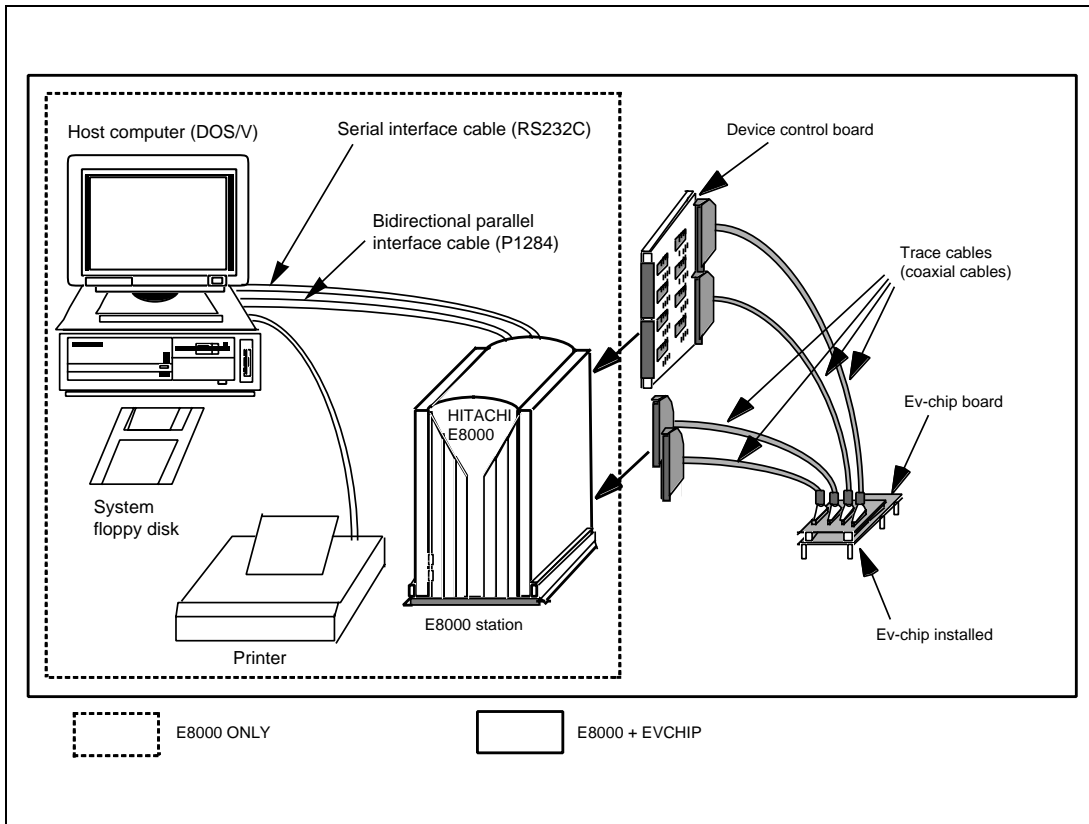


Figure 2.1 Test System Configuration

## Section 3 Diagnostic Program Function

### 3.1 General Description

The diagnostic program has three test-system configurations: E8000 ONLY test and E8000 + EVCHIP test (which are independent E8000 emulator system tests) and E8000 + EVCHIP + FIXED USER test. Note that the E8000 + EVCHIP + FIXED USER test cannot be executed, for it is the E8000 emulator system test at shipment and needs an additional system for testing.

### **CAUTION**

**Before executing an independent E8000 emulator system test, remove the EV-CHIP BOARD from the USER SYSTEM and USER SYSTEM INTERFACE CABLE. Correct test results cannot be obtained when the E8000 emulator is still connected to the user system.**

Independent E8000 emulator system tests:

1. E8000 Emulator System Test (E8000 ONLY)

The system configuration shown in figure 2.1 is used for testing the E8000 emulator system. The test results are displayed on the host computer display. After start-up, the system enters an endless test loop without operator intervention until an error is detected. When an error occurs and ERROR CONTINUE is not specified, the test is terminated. If ERROR CONTINUE is specified, the test resumes execution after an error content display. When initiating the diagnostic program, select whether to execute the following tests:

- Operation tests
- Serial interface test
- Bidirectional parallel interface test
- LAN board (optional) test

2. Test of E8000 Emulator, SH7060 Device Control Board, and SH7060 EV-Chip Board (E8000 + EVCHIP)

The system configuration shown in figure 2.1 is used for testing the E8000 emulator, and the SH7060 device control board and SH7060 EV-chip board for the E8000 emulator. The test results are displayed on the host computer display. After start-up, the system enters an endless test loop without operator intervention until an error is detected. When an error occurs and ERROR CONTINUE is not specified, the test is terminated. If ERROR CONTINUE is specified, the test resumes execution after an error content display. When initiating the diagnostic program, select whether to execute the following tests:

- Operation tests
- Serial interface test
- Bidirectional parallel interface test
- LAN board (optional) test

- Notes:
1. To stop diagnostic program execution, press the (CTRL) + C keys and interrupt the test.
  2. The bidirectional parallel interface and serial interface tests require additional circuits. Prepare the necessary circuits according to the diagrams in section 6, Testing Circuits and Connectors, before selecting the bidirectional parallel interface and serial interface tests.
  3. The LAN board must be installed in the E8000 station when performing the LAN board (optional) test.



### 3.2 Test Items

Test items are listed in table 3.1. The test items to be executed depend on the test system configuration.

Table 3.1 Diagnostic Program Test Items

No.	Test Item	Description	Executed or Not	
			E8000 ONLY	E8000 + EVCHIP
TEST01	FLASH MEMORY READ TEST	Control board flash memory test	O	O
TEST02	CONT WORK RAM TEST	Control board work RAM test	O	O
TEST03	SHARED RAM TEST	Trace board RAM test	O	O
TEST04	FIRM RAM TEST	Firmware RAM test	O	O
TEST05	OPTION I/F TEST	Optional host computer I/F DPRAM test	O	O
TEST06	LAN I/F TEST	LAN board interface test	X	X
TEST07	P1284 I/F TEST	Bidirectional parallel interface test	X	X
TEST08	SCI TEST	Serial interface test	X	X
TEST09	JTAG TEST	JTAG controller test	O	O
TEST10	CONT REG. TEST	Control board register test	O	O
TEST11	IDR READ TEST	E8000 hardware configuration check	O	O
TEST12	DIP SWITCH TEST	Control board DIP switch test	X	X
TEST13	TRACE REG. TEST	Trace board register test	O	O
TEST14	TRACE RAM TEST	Trace board RAM test	O	O
TEST15	PARALLEL RAM TEST	Parallel RAM test	O	O
TEST16	EBOX TEST	DCONT firmware and ID check		O
TEST17	ERAM WINDOW TEST	ERAM read/write test		O
TEST18	ERAM STEP TEST	ERAM step test		O
TEST19	ERAM HARD BREAK TEST1	ERAM hardware break test		O
TEST20	ERAM HARD BREAK TEST2	ERAM hardware break test		O
TEST21	ERAM SOFT BREAK TEST	ERAM software break test		O
TEST22	COMPULSORY BREAK TEST	CBR register break test		O

Table 3.1 Diagnostic Program Test Items (cont)

No.	Test Item	Description	Executed or Not	
			E8000 ONLY	E8000 + EVCHIP
TEST23	ERAM TRACE TEST	ERAM trace mode test		O
TEST24	ERAM TIME MEASURE TEST	Time measurement function check		O
TEST25	ERAM PARALLEL MONITOR TEST	ERAM parallel monitor test		O
TEST26	INROM WRITE PROTECT TEST	Internal ROM write protect test		O
TEST27	PC COVERAGE TEST	COVERAGE RAM read/write test		O

Notes: O: Executed without operator intervention

X: Executed when specified

None: Not executed

Note: If an error occurs and ERROR CONTINUE is not specified, displays an error message, stops test execution, and displays the following message:

Retry (Y/N) ?

If Y is entered, retests the test item wherein the error occurred.

If N is entered, displays the following message:

Continue (Y/N) ?

If Y is entered, quits testing the test item wherein the error occurred and goes on to the next test item.

If N is entered, displays the following message:

Abort (Y/N) ?

If Y is entered, resets the system software.

If N is entered, returns to the first message (Retry (Y/N) ?) and repeats the above procedure until Y is entered.

### 3.3 Operation Flowchart

Figure 3.1 shows the diagnostic program operation flowchart.

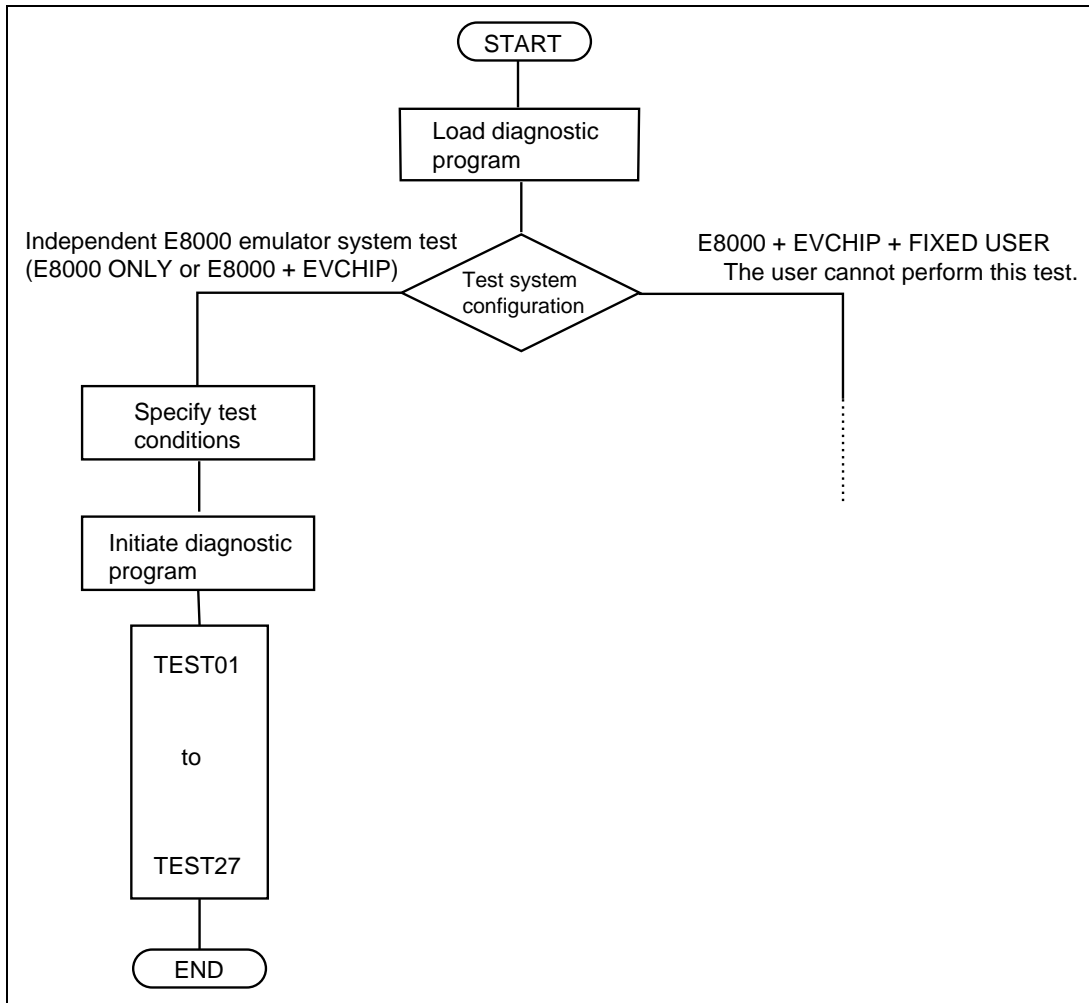


Figure 3.1 Diagnostic Program Operation Flowchart

Note: TEST06 is executed when the optional LAN board test is specified.  
TEST07 is executed when the bidirectional parallel interface test is specified.  
TEST08 is executed when the serial interface test is specified.  
TEST12 is executed when the operation tests are specified.  
TEST16 to TEST27 are not executed when the E8000 ONLY test is selected.

### 3.4 Data Output to the Printer

The following describes the process for sending diagnostic program execution results to the printer using the E8000 emulator.

#### Diagnostic Program Output to Printer

```
START E8000
  S: START E8000
  F: FLASH MEMORY TOOL
  L: SET LAN PARAMETER
  T: START DIAGNOSTIC TEST
  (S/F/L/T) ? >a:TM.LOG (RET)      (a)
  (S/F/L/T) ? t (RET)              (b)
```

(Diagnostic program execution)

```
(CTRL) + C      (c)
>q (RET)        (d)
```

```
E8000 MONITOR Vn.m
Copyright (C) Hitachi, Ltd. 1995
Licensed Material of Hitachi, Ltd.
```

TESTING

RAM 0123

```
START E8000
  S: START E8000
  F: FLASH MEMORY TOOL
  L: SET LAN PARAMETER
  T: START DIAGNOSTIC TEST
  (S/F/L/T) ? >- (RET)      (e)
```

- Notes: 1. Underlined sections should be entered by the user.  
2. (RET): RETURN key

Description:

- (a) Enter the following command after the emulator monitor command prompt.

>a:TM.LOG (RET)

In the above example, a indicates drive a and TM.LOG indicates the file name.

Note: When selecting drive a, insert the floppy disk in the floppy disk drive before executing this command.

- (b) Execute the diagnostic program.  
(c) Press the (CTRL) + C keys after executing the diagnostic program.  
(d) Enter the following command to return to the monitor command input wait state.

>q (RET)

- (e) Enter the following command in the monitor command input wait state to terminate data output to the file.

>- (RET)

- (f) Printing.

Open the file (TM.LOG) to which the diagnostic program execution results were output and output the data to a printer from the host computer used. The file can be opened from the existing editor of the host computer used.



## Section 4 Diagnostic Program Operation Procedures

This section describes the diagnostic program operation procedure.

### **WARNING**

**Always switch OFF all devices before connecting or disconnecting the E8000 EMULATOR and OTHER DEVICES. Failure to do so will result in a FIRE HAZARD and will damage the E8000 emulator and other devices, or will result in PERSONAL INJURY.**

The following describes the operation procedure when using the host interface software (IPW). When the diagnostic program is executed by using the ISA bus interface (PCI interface, PCMCIA interface, or LAN adapter is included), execute the program from the HDI. For HDI installation and diagnostic program operation, refer to sections 2 and 5 in the SH7060 E8000 Hitachi Debugging Interface User's Manual.

- Notes:
1. To execute the diagnostic program, DIAG.SYS must be installed in flash memory, according to the instructions in the SH7060 E8000 Emulator User's Manual (HS7060EDD81HE).
  2. Before executing the diagnostic program, make sure the DIP switches have the same settings as at shipment (refer to figure 4.1).
  3. When using the ISA bus interface, execute the diagnostic program from HDI.

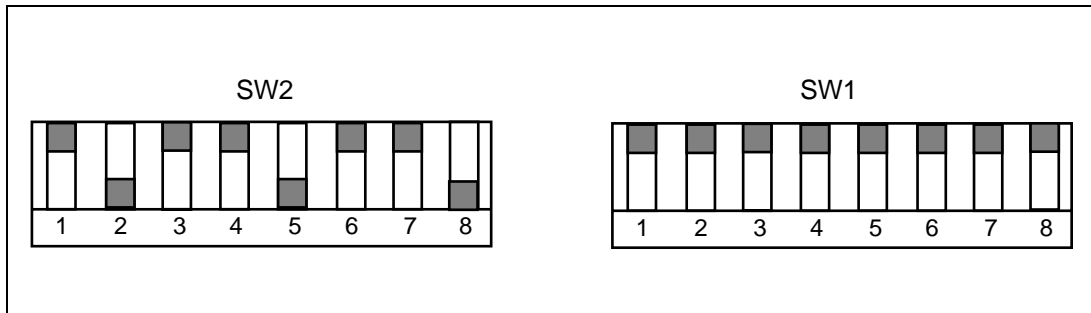


Figure 4.1 DIP Switch Setting at Shipment

## 4.1 Installation Procedure

To execute the diagnostic program, file DIAG.SYS must be installed in the E8000 emulator flash memory.

If the E8000 emulator is connected to the host computer via the bidirectional parallel interface, the diagnostic program can be loaded with the following procedure. Note that the system disk is assumed to be inserted in drive A of the host computer. It is assumed that E8000.SYS, SHCNF706.SYS, and SHDCT706.SYS has been installed. It takes approximately one minute.

Operations	Display Message
1. Initiate the E8000 system floppy disk IPW.	
2. Power on the E8000 emulator.	
3. Emulator monitor command prompt	START E8000 S:START E8000 F:FLASH MEMORY TOOL L:SET LAN PARAMETER T:START DIAGNOSTIC TEST (S/F/L/T) ? <u>F (RET)</u>
4. Enter F (RET) to initiate the flash memory management tool. The emulator displays prompt FM> and waits for a flash memory management tool command.	FM>
5. Enter SL (RET) to load the system program.	FM> <u>SL (RET)</u>
6. Enter 1 (RET) to select PC as the host computer type, and 2 (RET) to select parallel interface as the interface method.	SELECT LOAD No. (1:PC or 2:WS) ? <u>1 (RET)</u> SELECT INTERFACE (1:RS-232C or 2:PARALLEL) ? <u>2 (RET)</u>



Operations

Display Message

- |   |  |
|---|--|
| 7. Enter N (RET) to not load system program E8000.SYS.  | LOAD E8000 SYSTEM FILE OK (Y/N) ? <u>N (RET)</u>   |
| 8. Enter N (RET) to not load configuration file SHCNF706.SYS.   | LOAD CONFIGURATION FILE OK (Y/N) ? <u>N (RET)</u>  |
| 9. Enter N (RET) to not load firmware file SHDCT706.SYS.  | LOAD FIRMWARE FILE OK (Y/N) ? <u>N (RET)</u>   |
| 10. Enter N (RET) to not load the ITRON debugger.   | LOAD ITRON DEBUGGER FILE OK (Y/N) ? <u>N (RET)</u>   |
| 11. Enter Y (RET) to allow the diagnostic program file DIAG.SYS to be loaded. Then enter the parallel transfer command to load DIAG.SYS in the current directory on the host computer to the emulator flash memory. | LOAD DIAGNOSTIC FILE OK (Y/N) ? <u>Y (RET)</u><br>INPUT COMMAND : <u>#B:A:/DIAG.SYS (RET)</u><br><br>: COMPLETED                   |
| 12. Enter DIR (RET) to check whether the necessary files have been loaded.  | FM> <u>DIR (RET)</u><br><br><FILE ID> <STATUS><br>SYS OK<br>CONF OK<br>LAN NO<br>FIRM OK<br>TRON NO<br>DIAG OK<br>INI OK<br>MON OK |

## Operations

## Display Message

13. Enter Q (RET) to terminate the flash memory management tool.
- ```
FM> Q (RET)
START E8000
S:START E8000
F:FLASH MEMORY TOOL
L:SET LAN PARAMETER
T:START DIAGNOSTIC TEST
(S/F/L/T) ? _
```
14. Installation is completed.

## 4.2 Operation Procedure

All documents should contain the following section break and paragraph as the last item. The footers of this document refer to the paragraph in order to reference the last page of the document.

1. Correctly connect the following components.
  - E8000 emulator and host computer (RS232C interface)
  - E8000 emulator and EV-chip board (when the E8000 + EVCHIP test is selected)For other components, check connection according to the user system configuration. Remove the EV-chip board from the user system.
2. Turn on the following power supplies.
  - Host computer
  - E8000 emulatorFor other components, supply an appropriate voltage according to the user system configuration.
3. Start up the host interface software (IPW) on the host computer.

After the host interface software (IPW) is initiated, the E8000 emulator executes a self-diagnostic test which checks the internal RAM and the registers while displaying the starting message shown on the following figure. For details, refer to section 5, Troubleshooting, in the SH7060 E8000 Emulator User's Manual (HS7060EDD81HE).

```
EMULATOR INTERFACE (HS8000EIW01SF) Vn.m  
Copyright (C) Hitachi, Ltd. 1996  
Licensed Material of Hitachi, Ltd.
```

```
E8000 MONITOR (HS8000EST02SR) Vn.m  
Copyright (C) Hitachi, Ltd. 1995  
Licensed Material of Hitachi, Ltd.
```

```
TESTING
```

```
RAM    0123
```

```
START E8000
```

```
S:START E8000
```

```
F:FLASH MEMORY TOOL
```

```
L:SET LAN PARAMETER
```

```
T:START DIAGNOSTIC TEST
```

```
(S/F/L/T) ?
```

Figure 4.2 E8000 Emulator Starting Message

- Notes: 1. Underlined sections should be entered by the user. Both uppercase and lowercase letters are acceptable.
2. (RET): RETURN key
4. Load the diagnostic program according to the following procedure.

```
START E8000
S:START E8000
F:FLASH MEMORY TOOL
L:SET LAN PARAMETER
T:START DIAGNOSTIC TEST
  (S/F/L/T) ? T (RET)

E8000 EMULATOR TEST & MAINTENANCE PROGRAM (DIAG.SYS)
Version No.=x.xx mm/dd/yyyy

Copyright (C) Hitachi, Ltd. 1998
```

Figure 4.3 Loading Diagnostic Program

5. Specify the test condition.

When the diagnostic program is loaded and the following message is displayed on the host computer, select the desired test conditions.

```

Please, key in TEST PARAMETER

OPERATION TEST EXECUTE (Y/N) ? N (RET)           (a)
ERROR CONTINUE (Y/N) ? N (RET)                 (b)
TEST MODE SELECT
  1. E8000 ONLY
  2. E8000 + EVCHIP
  3. E8000 + EVCHIP + FIXED USER
TEST MODE (1/2/3) ? 2 (RET)                   (c)
DEVICE TYPE SH7060
RS232C LOOP CONNECTOR EXIST (Y/N) ? N (RET)   (d)
PARALLEL LOOP CONNECTOR EXIST (Y/N) ? N (RET) (e)
OPTION LAN BOARD EXIST (Y/N) ? N (RET)        (f)
START (Y/N) ? Y (RET)                         (g)

```

Figure 4.4 Test Condition Specifications

Description:

- (a) Only for tests requiring operator intervention. Enter Y to execute the operation tests. Otherwise, enter N.
  - (b) Y: Test continues when an error occurs.  
N: Test stops when an error occurs.
  - (c) 1: E8000 emulator system test (independent E8000 emulator system test)  
2: E8000 emulator, device control board, and EV-chip board test (independent E8000 emulator system test)  
3: E8000 emulator system test at shipment — cannot be used.
  - (d) Enter Y to execute the serial interface test. Otherwise, enter N.
  - (e) Enter Y to execute the bidirectional parallel interface test. Otherwise, enter N.
  - (f) Enter Y to execute the optional LAN board test. Otherwise, enter N.
  - (g) The test starts by entering Y. If N is entered, the diagnostic program main title will be displayed again.
6. Execute the diagnostic program using the procedure shown in figure 3.1.  
Execute each test item following the diagnostic program specifications. OK is displayed if a test is executed with no errors. An example of the E8000 + EVCHIP test is shown at the end of section 4.

7. For executing the bidirectional parallel interface test (TEST07)

To execute the bidirectional parallel interface test, install the P1284 loop connector described in section 6.1, Testing Circuit for P1284 I/F Test (TEST07), onto the bidirectional parallel interface connector on the E8000 emulator before executing the diagnostic program. Perform the following operations while executing the bidirectional parallel interface test.

Operation Procedures for TEST07 (P1284 I/F TEST):

(1) Before executing the diagnostic program, install the P1284 loop connector, as shown in figure 4.5.

(2) Enter Y to the following message at diagnostic program initiation:

```
PARALLEL LOOP CONNECTOR EXIST (Y/N) ? Y (RET)
```

(3) When the diagnostic program is executed, the bidirectional parallel interface test will be executed without operator interventions. If no error occurs, the following messages are displayed:

```
TEST07 P1284 I/F TEST      (COUNT = 001)
FIFO R/W TEST      OK
PARALLEL INTERRUPT TEST      OK
```

8. For executing the serial interface test (TEST08)

To execute the serial interface test, install the RS232C loop connector described in section 6.2, Testing Circuit for SERIAL I/F Test (TEST08), onto the serial interface connector on the E8000 emulator before executing the diagnostic program. Perform the following operations while executing the serial interface test.

Operation Procedures for TEST08 (SERIAL I/F TEST):

(1) Before executing the diagnostic program, install the RS232C loop connector, as shown in figure 4.5.

(2) Enter Y to the following message at diagnostic program initiation:

```
RS232C LOOP CONNECTOR EXIST (Y/N) ? Y (RET)
```

(3) When the diagnostic program is executed, the serial interface test will be executed without operator interventions. If no error occurs, the following message is displayed:

```
TEST08 SCI LOOP TEST      (COUNT = 001)      OK
```

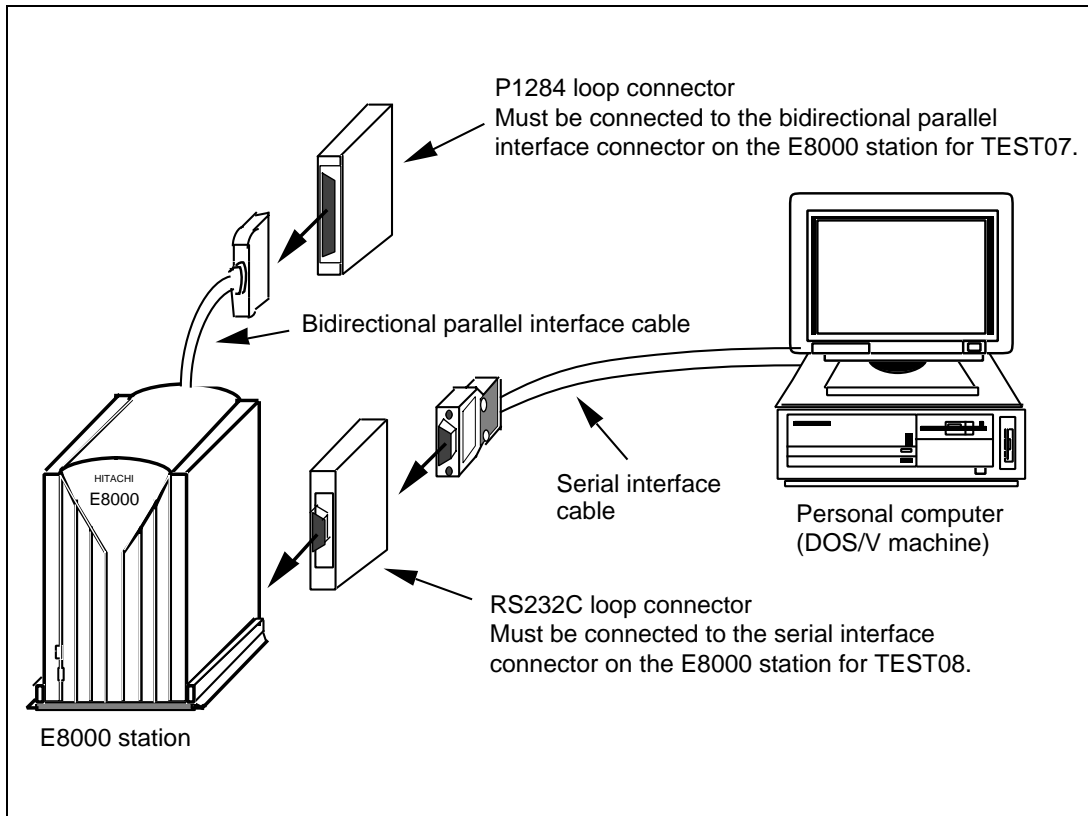


Figure 4.5 Loop Connector Installation

9. For executing the operation tests (TEST12)

To execute the operation tests, operator interventions are required during diagnostic program execution. Perform the following operations while executing the operation tests.

Operation Procedures for TEST12 (DIP SWITCH TEST):

(1) Enter Y to the following message at diagnostic program initiation:

```
OPERATION TEST EXECUTE (Y/N)? Y (RET)
```

(2) When the diagnostic program is executed, the E8000 emulator will halt at the following message and wait for command input:

```
TEST12 DIP SWITCH TEST      (COUNT = 001)
```

```
DIPSW 1 - 2 = 0092
```

```
DIPSW 1 - 2 = H'5555  SET OK (Y/N)
```

(3) After setting the DIP switches as shown in figure 4.6 (1), enter Y.

(4) If no error occurs, the following message is displayed:

```
DIPSWITCH 1 - 2 = H'5555  5555  OK
```

(5) The E8000 emulator will halt again at the following message:

DIPSW 1 - 2 = H'AAAA SET OK (Y/N)

(6) After setting the DIP switches as shown in figure 4.6 (2), enter Y.

(7) If no error occurs, the following message is displayed:

DIPSWITCH 1 - 2 = H'AAAA AAAA OK

(8) The E8000 emulator will halt again at the following message:

DIPSW 1 - 2 = 0092 SET OK (Y/N)

(9) After setting the DIP switches as shown in figure 4.6 (3), enter Y.

(10) If no error occurs, the following message is displayed:

DIPSWITCH 1 - 2 = 0092 0092 OK

TEST END

Note: (RET): RETURN key

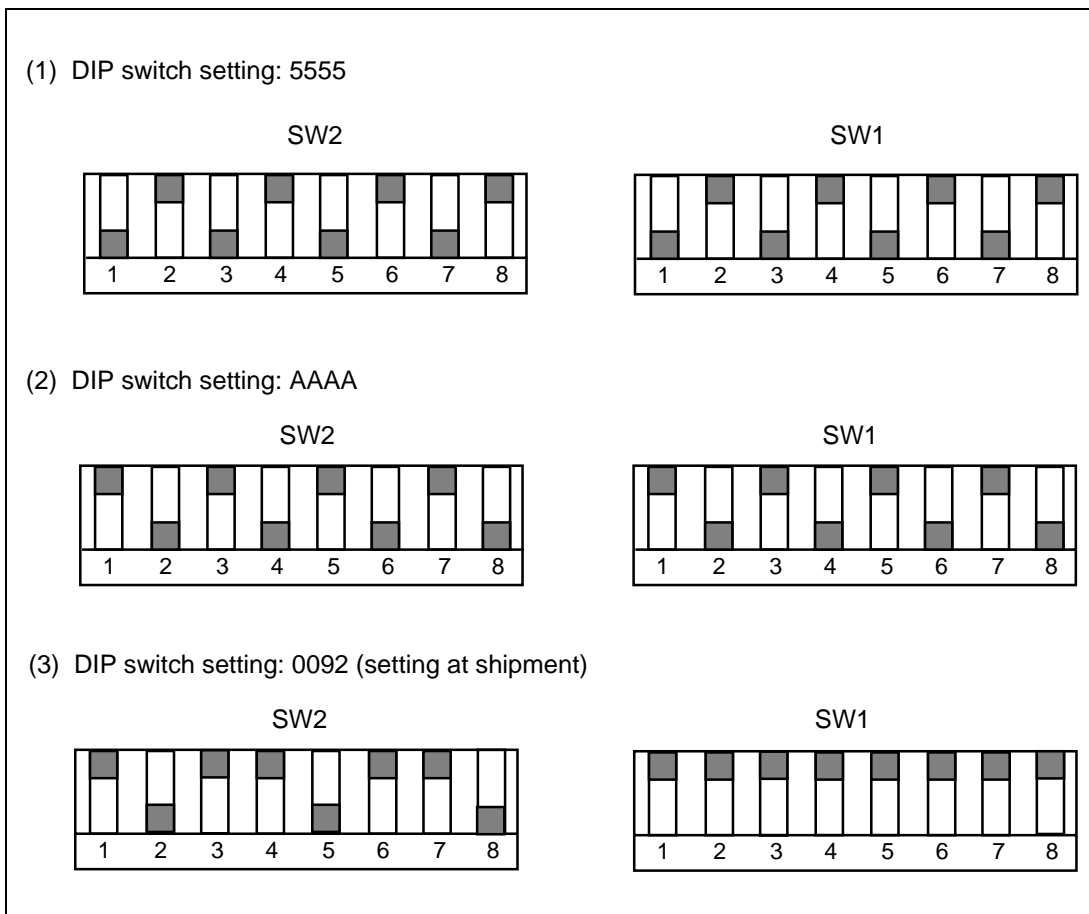


Figure 4.6 DIP Switch Settings



```

E8000 EMULATOR TEST & MAINTENANCE PROGRAM (DIAG.SYS)
  Version No. = x.xx mm/dd/yyyy (x.xx indicates the version number.)

Copyright (C) Hitachi, Ltd. 1998
Please, key in TEST PARAMETER

OPERATION TEST EXECUTE (Y/N) ? n
ERROR CONTINUE (Y/N) ? n
TEST MODE SELECT
  1. E8000 ONLY
  2. E8000 + EVCHIP
  3. E8000 + EVCHIP + FIXED USER
TEST MODE (1/2/3) ? 2

DEVICE TYPE SH7060
RS232C LOOP CONNECTOR EXIST (Y/N) ? n
PARALLEL LOOP CONNECTOR EXIST (Y/N) ? n
OPTION LAN BOARD EXIST (Y/N) ? n

START (Y/N) ? y

TEST01 FLASH MEMORY READ TEST      (COUNT = 001)
  (1) MONITOR SUM CHECK             OK
  (2) SYSTEM SUM CHECK              OK
  (3) EVCHIP FIRM SUM CHECK         OK
  (4) CONFIG SUM CHECK              OK
  (5) T/M SUM CHECK                 OK
  (6) LAN SUM CHECK
    NO LAN FILE
  (7) ITRON SUM CHECK
    NO TRON FILE
TEST02 CONT WORK RAM TEST          (COUNT = 001)
  (1) PAUSE TEST                    OK
  (2) MARCHING TEST                 OK

```

Figure 4.7 Diagnostic Program Output Example (E8000 + EVCHIP Test)

```

TEST03 SHARED RAM TEST          (COUNT = 001)
    (1) PAUSE TEST              OK
    (2) MARCHING TEST          OK
TEST04 FIRM RAM TEST           (COUNT = 001)
    (1) PAUSE TEST              OK
    (2) MARCHING TEST          OK
TEST05 OPTION I/F TEST        (COUNT = 001)
    (1) DPRAM PAUSE TEST       OK
    (2) DPRAM MARCHING TEST    OK
TEST09 JTAG TEST              (COUNT = 001) OK
TEST10 CONT REG. TEST         (COUNT = 001) OK
TEST11 IDR READ TEST          (COUNT = 001)
ID CODE = FCFE
PC I/F BOARD : DISCONNECT
TRC BOARD   : CONNECT
DCONT BOARD : CONNECT
EVCH BOARD  : CONNECT
LAN BOARD   : DISCONNECT
TEST13 TRACE REG. TEST       (COUNT = 001) OK
TEST14 TRACE RAM TEST        (COUNT = 001)
    (1) PAUSE TEST            OK
    (2) MARCHING TEST         OK
TEST15 PARALLEL RAM TEST     (COUNT = 001)
    (1) PAUSE TEST            OK
    (2) MARCHING TEST         OK
TEST16 EBOX TEST             (COUNT = 001)
    (1) EBOX ID CODE          OK
    (2) EBOX ID CHECK         OK
    (3) SHARED RAM TEST       OK
    (4) WORK RAM TEST         OK
    (5) ULSR TEST             OK
    (6) MAPR R/W TEST         OK

```

Figure 4.7 Diagnostic Program Output Example (E8000 + EVCHIP Test) (cont)

```

TEST17 ERAM WINDOW TEST          (COUNT = 001)
      (1) ERAM WINDOW TEST1      OK
      (2) ERAM WP TEST           OK
      (3) ERAM GOD TEST          OK
TEST18 ERAM STEP TEST            (COUNT = 001) OK
TEST19 ERAM HARD BREAK TEST1     (COUNT = 001)
      (1) UBC HARDBREAK TEST     OK
      (2) CHA0-7 HARDBREAK TEST  OK
      (3) CHB0-7 HARDBREAK TEST  OK
      (4) CHC0-7 HARDBREAK TEST  OK
TEST20 ERAM HARD BREAK TEST2     (COUNT = 001)
      (1) SEQUENTIAL BREAK TEST  OK
      (2) RAR OVERFLOW BREAK TEST OK
      (3) CHC TIMEOUT BREAK TEST  OK
      (4) CHB0 INTERRUPT TEST    OK
TEST21 ERAM SOFT BREAK TEST      (COUNT = 001) OK
TEST22 COMPULSORY BREAK TEST     (COUNT = 001) OK
TEST23 ERAM TRACE TEST          (COUNT = 001)
      (1) SUBROUTINE TRACE TEST   OK
      (2) RANGE TRACE TEST        OK
      (3) SUBROUTINE/RANGE TRACE TEST OK
      (4) TRACE STOP TEST         OK
      (5) TRACE SPECIAL CONDITION TEST OK
      (6) INRAM TRACE TEST        OK
      (7) ERAM CONTINOUS ACCESS TEST OK
TEST24 ERAM TIME MEASURE TEST    (COUNT=001)
      (1) SUBROUTINE TIME MEASURE TEST1 OK
      (2) SUBROUTINE TIME MEASURE TEST2 OK
      (3) SUBROUTINE TIME MEASURE TEST3 OK
      (4) TIME STUMP TEST         OK
      (5) A to B TIME MEASURE TEST OK

```

Figure 4.7 Diagnostic Program Output Example (E8000 + EVCHIP Test) (cont)

|               |                               |                      |     |
|---------------|-------------------------------|----------------------|-----|
| TEST25        | ERAM PARALLEL MONITOR TEST    | (COUNT=001)          | OK  |
| TEST26        | INROM WRITE PROTECT TEST      | (COUNT=001)          | OK  |
| TEST27        | PC COVERAGE TEST              | (COUNT=001)          |     |
| <u>TEST01</u> | <u>FLASH MEMORY READ TEST</u> | <u>(COUNT = 002)</u> |     |
| (a)           | (b)                           | (c)                  |     |
| (1)           | MONITOR SUM CHECK             | <u>OK</u>            | (d) |

Figure 4.7 Diagnostic Program Output Example (E8000 + EVCHIP Test) (cont)

Description:

- (a) Test item number
- (b) Test item
- (c) Execution count
- (d) Test result

## Section 5 Error Handling

If an error occurs, provide a Hitachi sales agency with a detailed description of the problem.



## Section 6 Testing Circuits and Connectors

### 6.1 Testing Circuit for P1284 I/F TEST (TEST07)

Connect the testing circuit that forms the loop in figure 6.1 to the bidirectional parallel interface connector on the E8000 emulator.

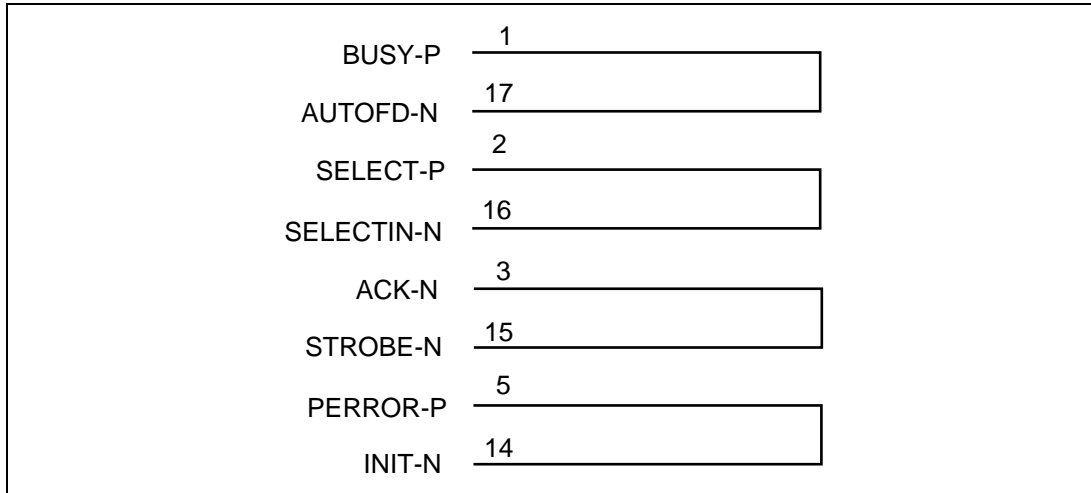


Figure 6.1 Testing Circuit for P1284 Loop Back Test

### 6.2 Testing Circuit for SERIAL I/F TEST (TEST08)

Connect the testing circuit in figure 6.2 to the serial interface connector on the E8000 emulator.

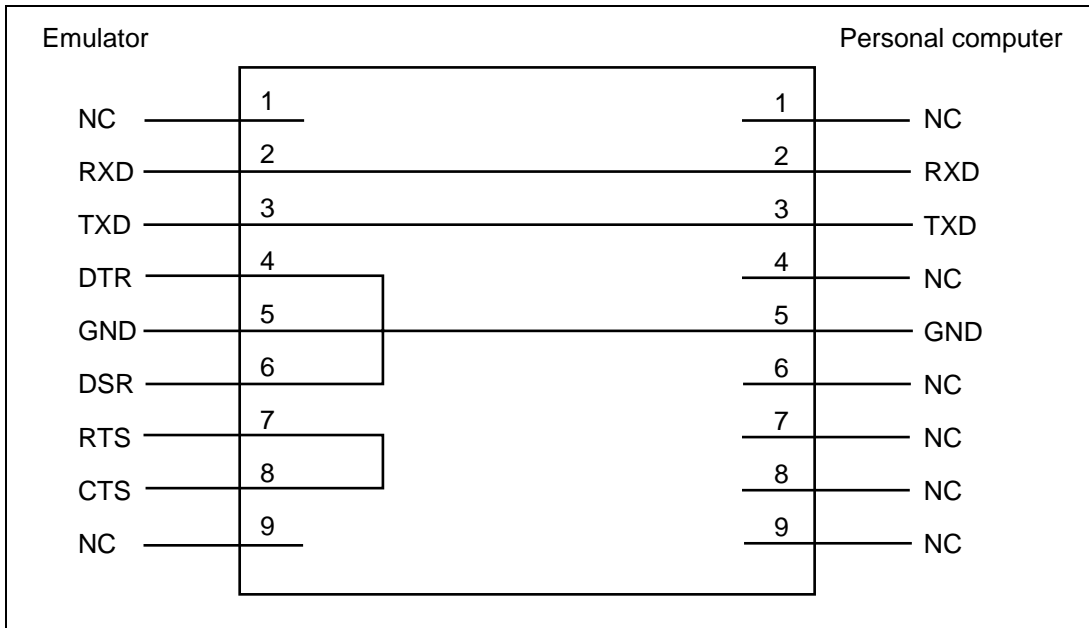


Figure 6.2 Testing Circuit for SERIAL I/F Test



### 6.3 Serial Interface Connector

Figure 6.3 shows pin locations in the serial interface connector on the E8000 emulator. Table 6.1 lists the signal name of each pin.

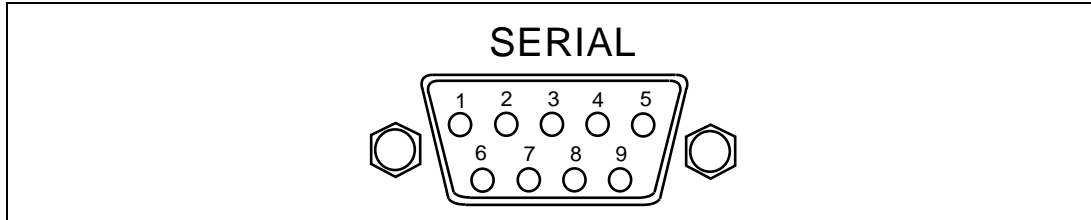


Figure 6.3 Pin Locations in E8000 Emulator Serial Interface Connector

Table 6.1 Pin Signal Names in E8000 Emulator Serial Interface Connector

| Pin No. | Signal Name | Pin No. | Signal Name |
|---------|-------------|---------|-------------|
| 1 and 9 | NC          | 5       | GND         |
| 2       | RXD         | 6       | DSR         |
| 3       | TXD         | 7       | RTS         |
| 4       | DTR         | 8       | CTS         |

### 6.4 Bidirectional Parallel Interface Connector

Figure 6.4 shows pin locations in the bidirectional parallel interface connector on the E8000 emulator. Table 6.2 lists the signal name of each pin.

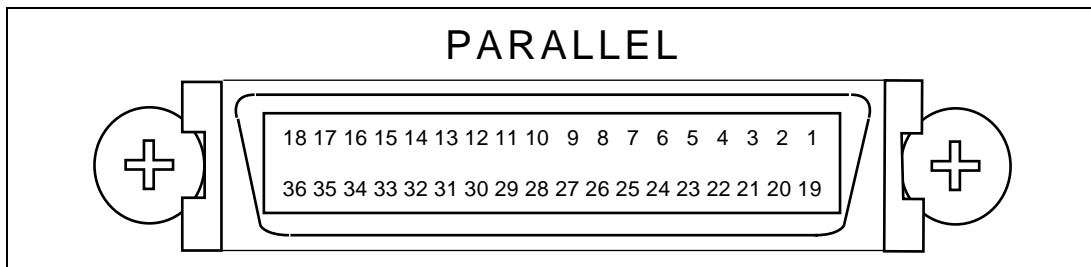


Figure 6.4 Pin Locations in E8000 Emulator Bidirectional Parallel Interface Connector

Table 6.2 Pin Signal Names in E8000 Emulator Bidirectional Parallel Interface Connector

| <b>Pin No.</b> | <b>Signal Name</b> | <b>Pin No.</b> | <b>Signal Name</b>  |
|----------------|--------------------|----------------|---------------------|
| 1              | BUSY-P             | 11             | SD5-P               |
| 2              | SELECT-P           | 12             | SD6-P               |
| 3              | ACK-N              | 13             | SD7-P               |
| 4              | FAULT-N            | 14             | INIT-N              |
| 5              | PERROR-P           | 15             | STROBE-N            |
| 6              | SD0-P              | 16             | SELECTIN-N          |
| 7              | SD1-P              | 17             | AUTOFD-N            |
| 8              | SD2-P              | 18             | HOSTLOGICHIGH       |
| 9              | SD3-P              | 36             | PERIPHERALLOGICHIGH |
| 10             | SD4-P              | 19 to 35       | GND                 |